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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: Stolte, et al.  
Serial No.: 09/922,115  
Filed: August 3, 2001  
For: WAVELENGTH MEASUREMENT ADJUSTMENT  
Art Unit: 2877  
Examiner: Lyons, Michael A.

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TECHNOLOGY CENTER 2800

Attorney Docket: 987.0023USU

**AMENDMENT AND RESPONSE**

Box: Non Fee Amendment  
Assistant Commissioner for Patents  
Washington, D.C. 20231

Dear Sir:

In response to the Office Action dated November 20, 2002, please amend the above-noted application as follows:

**IN THE SPECIFICATION**

Please replace the paragraph commencing at page 3, line 15 with the following new paragraph:

B1  
---A preferred embodiment of the wavemeter unit makes use of the interferometric principle, such as the Fizeau, Michelson or Fabry-Perot interferometer or uses e.g. a combination of different etalons (which can be also realized based on polarization effects) as disclosed in detail in the aforementioned EP-A- 875743. Those interferometric units generally provide a